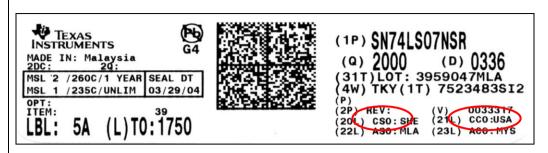
PCN Number:		20131025001D							PCN Date: 06/11/2014		
Title: Qualification of Vanguard Facility as an additional FAB site source for select OPA340xx and OPA2336xx devices in the 0.60UM process technology											
Customer Contact:		PCN Manager Phone				Phone	+1(214)480-	6037	Dept:	Quality Services	
*Proposed 1 st Ship D		09/11/2014			Estimated Sample Availability:			Date provided at sample request.			
Change	Туре:						<u>-</u>				
Ass	embly Site		Design					Wafer Bu	ımp Site		
Ass	embly Process				ata Sh			Wafer Bu	er Bump Material		
Ass	embly Materia	ls	Par		art nun	number change			ımp Process		
	hanical Specif				_	est Site			Wafer Fa		
L Pac	king/Shipping/	<u>Labeli</u>	eling		est Pro	ocess			b Materials		
							Wafer Fa	ib Process			
						PCN I	Details				
Descrip	tion of Chang	je:									
is now of Product This noting additional	system error causing them not to appear in Page 2 of your notification letter. This error is now corrected. The affected devices are highlighted in yellow with bold font in the Product Affected Section of this document. This notification is to announce the qualification of the Vanguard fabrication facility as an additional wafer FAB source for select OPA340xx and OPA2336xx devices listed in "Product Affected" section.										
		tes, Process, wafer dia.				dia.	Additional Site, Process, wafer dia.				
TMSC-V	VF2, 0.60UM,	200mr	n				Vanguard, VI	M/0.6UM DPDM, 200mm			
Qualifica	Qualification details are provided in the Qual Data Section.										
	for Change:										
	ty of Supply										
Anticipa	ated impact of	n For	m, Fit	, Fı	ınc	tion, Q	uality or Relia	bilit	y (positiv	e / negative):	
None											
Changes to product identification resulting from this PCN:											
Current											
C	hip Site	Chip	site co	de	(20	L)	Chip country code	(21	_)		
TS	TSMC-WF2 TS2		TS2			TWN					
New		ı									
	hip Site	Chip	site co		(20	L)	Chip country code	e (21)	_)		
Vang	Vanguard (VIS) VAN				TWN						

Sample product shipping label (not actual product label)



Product Affected: Corrected Device List					
OPA2336EA/250	OPA2336P	OPA340UA/2K5G4	OPA2336E/250G4		
OPA2336EA/2K5G4	OPA340UA	OPA2336E/2K5G4	OPA2336UAG4		
OPA2336UA/2K5G4	OPA2336U	OPA2336UA	OPA340PAG4		
OPA340UA/2K5	OPA2336EA/2K5	OPA340NA/3KG4	OPA2336PG4		
OPA340PA	OPA2336PA	OPA340NA/250	OPA2336UG4		
OPA2336UA/2K5	OPA2336EA/250G4	OPA340NA/250G4	OPA340-W		
OPA2336U/2K5	OPA2336E/2K5	OPA340NA/3K	OPA2336PAG4		
OPA2336U/2K5G4	OPA340UAG4	OPA2336E/250			

Qualification Report

OPA340 and OPA2336 will transfer from TSMC Fab 2 to Vanguard aka VIS FAB - qualified process flow (0.5um/0.6um) model transfer from TSMC FAB2

Approved04/26/2014

Product Attributes

Attributes	Qual Device: OPA2336EA	Qual Device: OPA340NA	QBS Process: DDC112Y	QBS Process: TSC2046IPW	QBS Process: OPA356AQDBVRQ1
Assembly Site	ASESH	NS2	CRS	TAI	NFME
Package Family	VSSOP	SOT	TQFP	TSSOP	SOT
Flammability Rating	UL 94 V-0	UL 94 V-0	UL94 Class V-0	UL94 Class V-0	UL 94 V-0
Wafer Fab Supplier	Vanguard	Vanguard	Vanguard	Vanguard	Vanguard
Wafer Fab Process	0.5/0.6UM	0.5/0.6UM	0.5/0.6UM	0.5/0.6UM	0.5/0.6UM

- QBS: Qual By Similarity
- Qual Device OPA2336EA is qualified at LEVEL2-260C
- Qual Device OPA340NA is qualified at LEVEL1-260C

Test Name / Condition	Duration	Qual Device: OPA2336EA	Qual Device: OPA340NA	QBS Process: DDC112Y	QBS Process: TSC2046IPW	QBS Process: OPA356AQDBVRQ1
Biased HAST, 130C/85%RH	96 Hours	-	-	1/77/0	1/77/0	2/154/0
Autoclave 121C	96 Hours	-	-	1/77/0	1/77/0	2/154/0
Unbiased HAST 130C/85%RH	u6 Houre		-	-	-	1/77/0
Temperature Cycle, - 65/150C			-	1/77/0	1/77/0	2/153/0
High Temp Storage Bake 175C	500 Hours	-	-	-	-	1/45/0
High Temp Storage Bake 150C				1/77/0	-	-
High Temp Storage Bake 170C	420 Hours	-	-	-	1/77/0	-
Life Test, 150C	1000 Hours	-	-	1/116/0	-	-
Life Test, 125C	1000 Hours	-	-	-	-	2/158/0
Early Life Failure Rate, 125C	48 Hours	-	-	-	-	3/2400/0
ESD - HBM	1000 V	1/3/0	1/3/0	1/3/0	1/3/0	-
ESD - CDM	250 V	1/3/0	1/3/0	1/3/0	1/3/0	1/3/0
Latch-up	(per JESD78)	1/6/0	1/6/0	1/6/0	-	1/6/0
Electrical Distributions Cpk>1.67 Room, hot, and cold test		-	-	-	-	1/90/0
Electrical Per Datasheet Characterization Parameters		1/Pass	1/Pass	1/Pass	1/Pass	

⁻ Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable

Green/Pb-free Status:
Qualified Pb-Free(SMT) and Green

For questions regarding this notice, e-mails can be sent to the regional contacts shown below or your local Field Sales Representative.

Location	E-Mail
USA	PCNAmericasContact@list.ti.com
Europe	PCNEuropeContact@list.ti.com
Asia Pacific	PCNAsiaContact@list.ti.com
Japan	PCNJapanContact@list.ti.com

⁻ The following are equivalent HTOL options based on an activation energy of 0.7eV: 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours

- The following are equivalent HTSL options based on an activation energy of 0.7eV: 150C/1k Hours, and 170C/420 Hours

⁻ The following are equivalent Temp Cycle options per JESD47: -55C/125C/700 Cycles and -65C/150C/500 Cycles Quality and Environmental data is available at TI's external Web site: http://www.ti.com/